


		Attorney Docket Number	1011-67627-01		
		Application Number	10/781,031		
		Filing Date	February 17, 2004		
		First Named Inventor	Rajski		
		Art Unit	2193		
		Examiner Name	David H. Malzahn		
<b>U.S. PATENT DOCUMENTS</b>					
Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.					
Examiner's Initials*	Cite No. (optional)	Number	Issue or Publication Date	Name of Applicant or Patentee	
		6,874,109	3.29.2005	Rajski et al.	
		US-2003/0120988	6.26.2003	Rajski et al.	
		US-2003/0131298	7.10.2003	Rajski et al.	
		US-2004/0128599	7.1.2004	Rajski et al.	
		US-2005/0015688	1.20.2005	Rajski et al.	
		US-2005/0097419	5.5.2005	Rajski et al.	
<b>FOREIGN PATENT DOCUMENTS</b>					
Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee
		Japan	01-239486 (with translation)	9.25.1989	Masaaki
		Japan	03-002579 (with translation)	1.8.1991	Shuichi et al.
		WIPO	WO 91/10182	7.11.1991	Alspector et al.
Examiner's Initials*	Cite No. (optional)	<b>OTHER DOCUMENTS</b>			



EXAMINER SIGNATURE: 12. H. MalzahnDATE CONSIDERED: 4/12/06

\* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	Attorney Docket Number	1011-67627-01	
	Application Number	10/781,031	
	Filing Date	February 17, 2004	
	First Named Inventor	Rajski	
	Art Unit	2193	
		Examiner Name	David H. Malzahn

### U.S. PATENT DOCUMENTS



Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
		6,272,653	8.27.2001	Amstutz
		6,308,291	10.23.2001	Kock et al.

### FOREIGN PATENT DOCUMENTS

Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee

### OTHER DOCUMENTS

Examiner's Initials*	Cite No. (optional)	
		Aitken et al., "A Diagnosis Method Using Pseudo-Random Vectors Without Intermediate Signatures," <i>Proc. ICCAD</i> , pp. 574-577 (1989).
		Bardell et al., <u>Built-In Test for VLSI Pseudorandom Techniques</u> , Chapter 4, "Test Response Compression Techniques," John Wiley & Sons, Inc., pp. 89-108 (1987).
		Benowitz et al., "An Advanced Fault Isolation System for Digital Logic," <i>IEEE Transactions on Computers</i> , Vol. C-24, No. 5, pp. 489-497 (May 1975).
		Chakrabarty et al., "Optimal Zero-Aliasing Space Compaction of Test Responses," <i>IEEE Transactions on Computers</i> , Vol. 47, No. 11, pp. 1171-1187 (November 1998).
		Chakrabarty, "Zero-Aliasing Space Compaction Using Linear Compactors with Bounded Overhead," <i>IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems</i> , Vol. 17, No. 5, pp. 452-457 (May 1998).

EXAMINER SIGNATURE: <u>D. H. Malzahn</u>	DATE CONSIDERED: <u>4/12/06</u>
--	---------------------------------

\* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	Attorney Docket Number	1011-67627-01
	Application Number	10/781,031
	Filing Date	February 17, 2004
	First Named Inventor	Rajski
	Art Unit	2193
	Examiner Name	David H. Malzahn

Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
		Ghosh-Dastidar et al., "Fault Diagnosis in Scan-Based BIST Using Both Time and Space Information," <i>Proc. ITC</i> , pp. 95-102 (September 1999).
		Karpovsky et al., "Board-Level Diagnosis by Signature Analysis," <i>Proc. ITC</i> , pp. 47-53 (1988).
		Karpovsky et al., "Design of Self-Diagnostic Boards by Multiple Signature Analysis," <i>IEEE Transactions on Computers</i> , Vol. 42, No. 9, pp. 1035-1044 (September 1993).
		Kundu, "On Diagnosis of Faults in a Scan-Chain," <i>Proc. VLSI Test Symp.</i> , pp. 303-308 (1993).
		Narayanan et al., "An Efficient Scheme to Diagnose Scan Chains," <i>Proc. ITC</i> , pp. 704-713 (1997).
		Rajski et al., <u>Arithmetic Built-In Self-Test for Embedded Systems</u> , Chapter 3, "Test Response Compaction," and Chapter 4, "Fault Diagnosis," Prentice Hall PTR, pp. 87-133 (1998).
		Rajski et al., "Diagnosis of Scan Cells in BIST Environment," <i>IEEE Transactions on Computers</i> , Vol. 48, No. 7, pp. 724-731 (July 1999).
		Saluja et al., "Testing Computer Hardware through Data Compression in Space and Time," <i>Proc. ITC</i> , pp. 83-88 (1983).
		Wu et al., "Scan-Based BIST Fault Diagnosis," <i>IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems</i> , Vol. 18, No. 2, pp. 203-211 (February 1999).

EXAMINER SIGNATURE: <u>D. H. Malzahn</u>	DATE CONSIDERED: <u>4/12/06</u>
<p>* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	